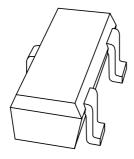
DISCRETE SEMICONDUCTORS

DATA SHEET



1PS181High-speed double diode

Product data sheet Supersedes data of April 1996 1996 Sep 03



High-speed double diode

1PS181

FEATURES

- Small plastic SMD package
- High switching speed: max. 4 ns
- Continuous reverse voltage: max. 80 V
- Repetitive peak reverse voltage: max. 85 V
- Repetitive peak forward current: max. 500 mA.

APPLICATIONS

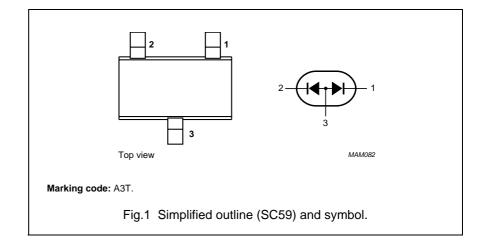
 High-speed switching in e.g. surface mounted circuits.

DESCRIPTION

The 1PS181 consists of two high-speed switching diodes with common anodes, fabricated in planar technology, and encapsulated in the small plastic SMD SC59 package.

PINNING

PIN	DESCRIPTION
1	cathode (k1)
2	cathode (k2)
3	common anode



LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
Per diode	Per diode				
V _{RRM}	repetitive peak reverse voltage		-	85	V
V_R	continuous reverse voltage		-	80	V
I _F	continuous forward current	single diode loaded; see Fig.2; note 1	_	215	mA
		double diode loaded; see Fig.2; note 1	_	125	mA
I _{FRM}	repetitive peak forward current		_	500	mA
I _{FSM}	non-repetitive peak forward current	square wave; T _j = 25 °C prior to surge			
		t = 1 μs	_	4	Α
		t = 1 s	_	0.5	Α
P _{tot}	total power dissipation	T _{amb} = 25 °C; note 1	_	250	mW
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		_	150	°C

Note

1. Device mounted on an FR4 printed-circuit board.

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High-speed double diode

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ELECTRICAL CHARACTERISTICS

 $T_j = 25$ °C; unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	TYP.	MAX.	UNIT
Per diode	Per diode				
V _F	forward voltage	see Fig.3			
		I _F = 1 mA	610	_	mV
		I _F = 10 mA	740	_	mV
		I _F = 50 mA	_	1.0	V
		I _F = 100 mA	_	1.2	V
I _R	reverse current	see Fig.4			
		V _R = 25 V	_	30	nA
		V _R = 80 V	_	0.5	μΑ
		V _R = 25 V; T _j = 150 °C	_	30	μΑ
		$V_R = 80 \text{ V}; T_j = 150 ^{\circ}\text{C}$	_	100	μΑ
C _d	diode capacitance	f = 1 MHz; V _R = 0; see Fig.5	_	2.0	pF
t _{rr}	reverse recovery time	when switched from I_F = 10 mA to I_R = 10 mA; R_L = 100 Ω ; measured at I_R = 1 mA; see Fig.6	_	4	ns
V _{fr}	forward recovery voltage	when switched from $I_F = 10$ mA; $t_r = 20$ ns; see Fig.7	-	1.75	V

THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	CONDITIONS	VALUE	UNIT
R _{th j-tp}	thermal resistance from junction to tie-point		250	K/W
R _{th j-a}	thermal resistance from junction to ambient	note 1	500	K/W

Note

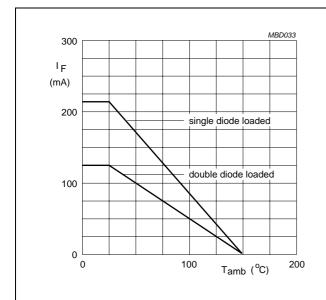
1. Device mounted on an FR4 printed-circuit board.

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High-speed double diode

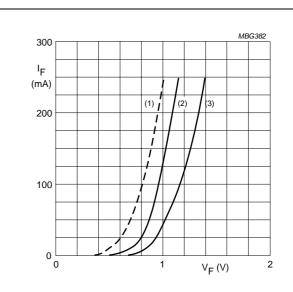
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GRAPHICAL DATA



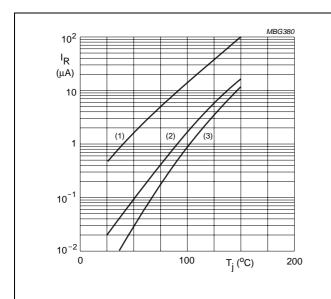
Device mounted on an FR4 printed-circuit board.

Fig.2 Maximum permissible continuous forward current as a function of ambient temperature.



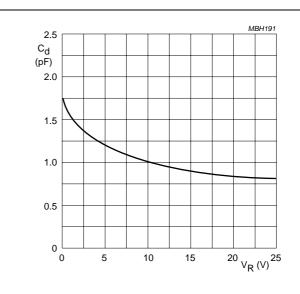
- (1) $T_j = 150 \,^{\circ}\text{C}$; typical values.
- (2) $T_j = 25$ °C; typical values.
- (3) $T_j = 25$ °C; maximum values.

Fig.3 Forward current as a function of forward voltage.



- (1) $V_R = 80 \text{ V}$; maximum values.
- (2) $V_R = 80 \text{ V}$; typical values.
- (3) $V_R = 25 \text{ V}$; typical values.

Fig.4 Reverse current as a function of junction temperature.



f = 1 MHz; $T_j = 25 \,^{\circ}\text{C}$.

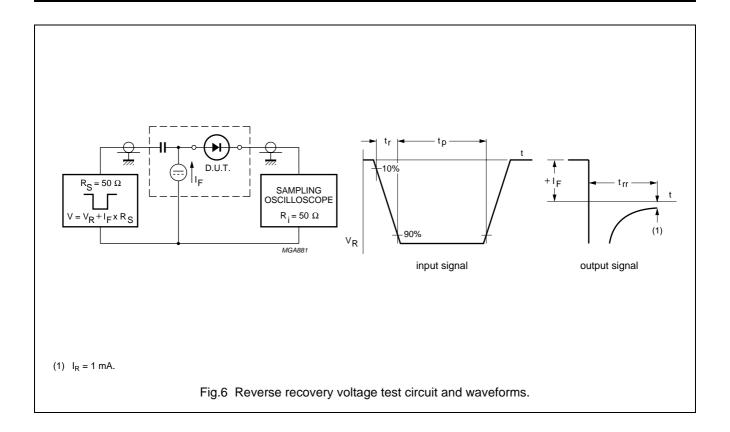
Fig.5 Diode capacitance as a function of reverse voltage; typical values.

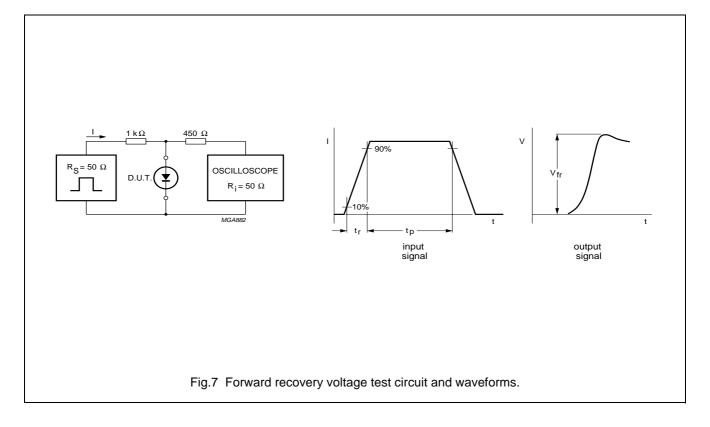
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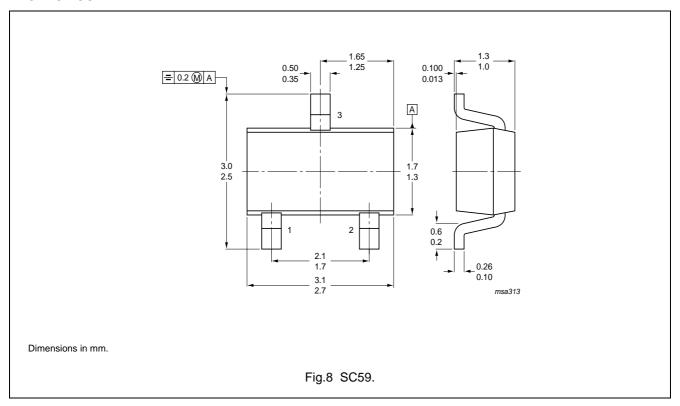


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PACKAGE OUTLINE



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DATA SHEET STATUS

DOCUMENT STATUS ⁽¹⁾	PRODUCT STATUS ⁽²⁾	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

Notes

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- 2. The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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